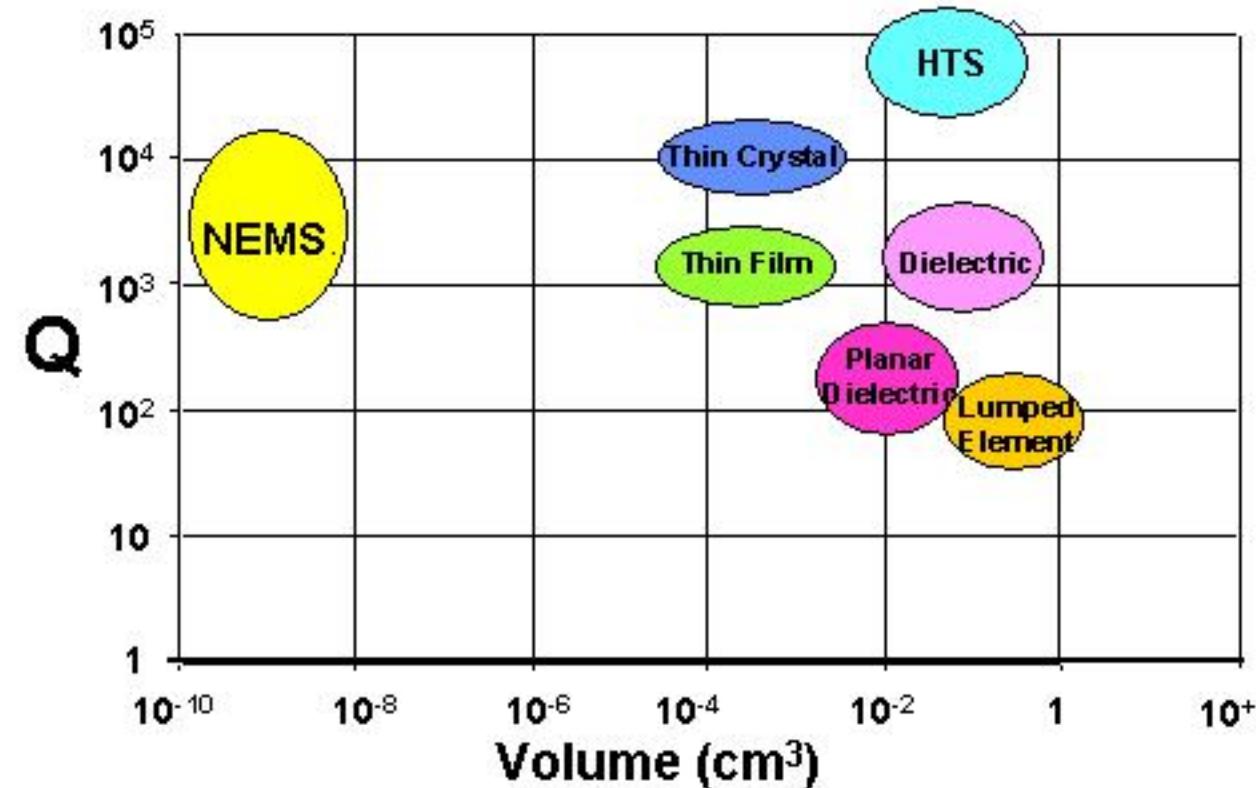


# High-Q Piezoelectric Nanomechanical Filter Arrays

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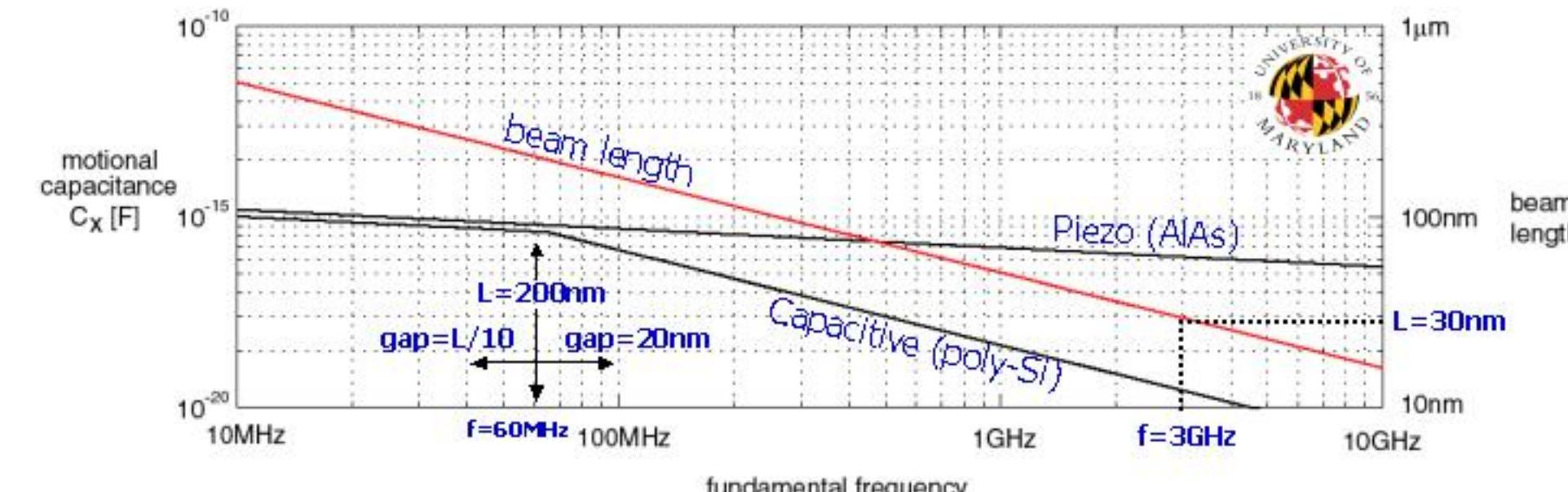
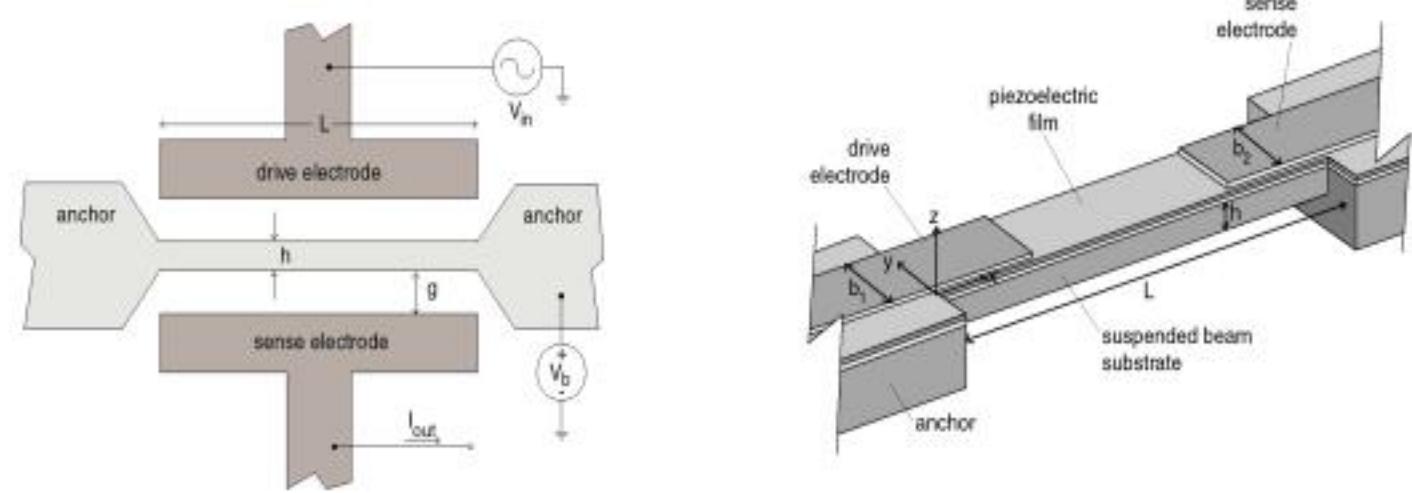
## Project Goals

- Functional filter banks based on nano-scale piezoelectric structures:**
  - orders-of-magnitude size reduction compared to SAW devices
  - direct integration with VLSI (ZnO) and high-speed electronics (AlAs)
  - low power operation

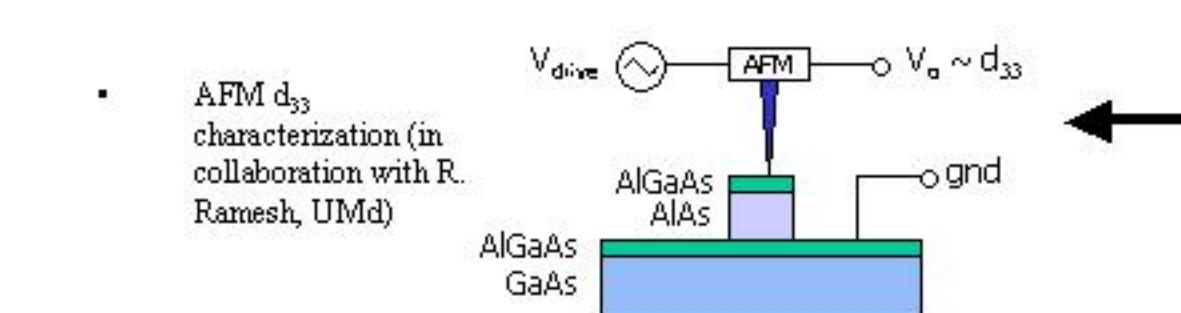
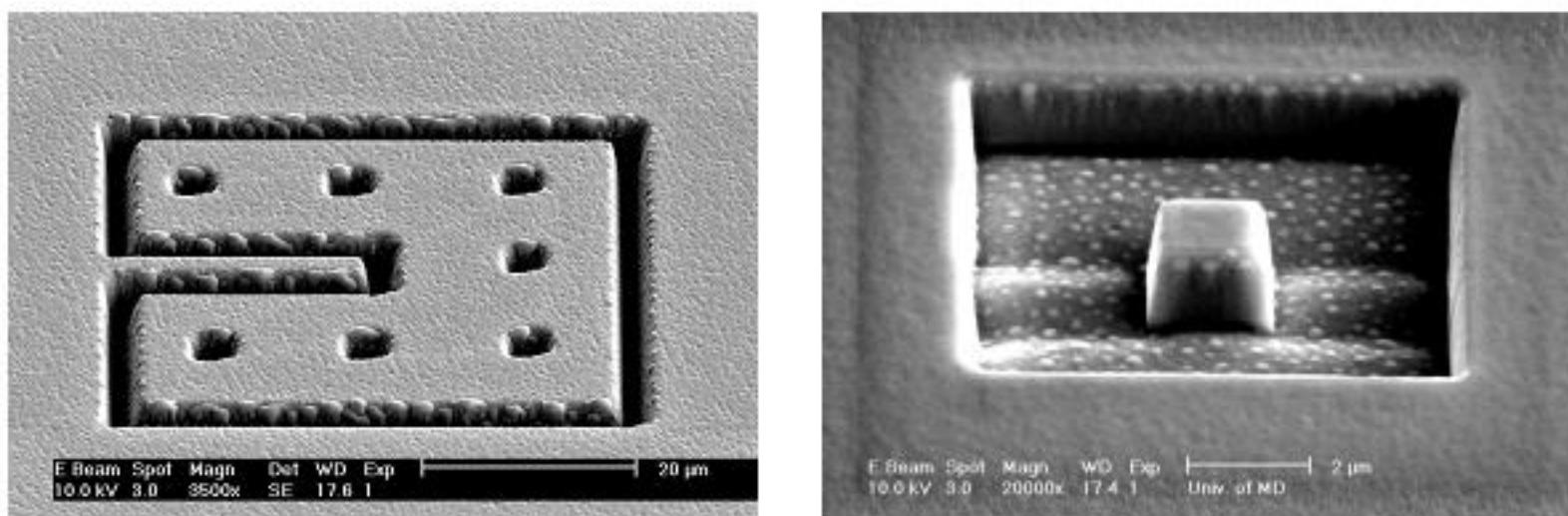


## Why piezoelectric filters?

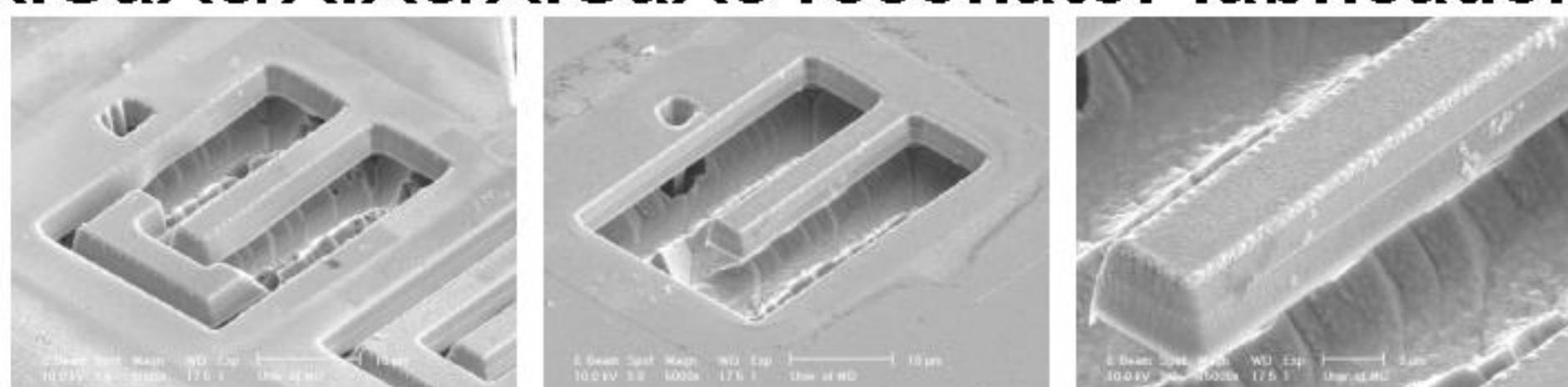
- Piezoelectric coupling scales into the nano regime much more favorably than capacitive coupling for lower insertion loss, higher SNR
- High-Q single crystal piezoelectric materials, e.g. AlAs, will enable direct integration with high speed electronics, optoelectronics
- Comparison of displacement-based capacitive and strain-based piezoelectric doubly-clamped beam resonators up to 10GHz:



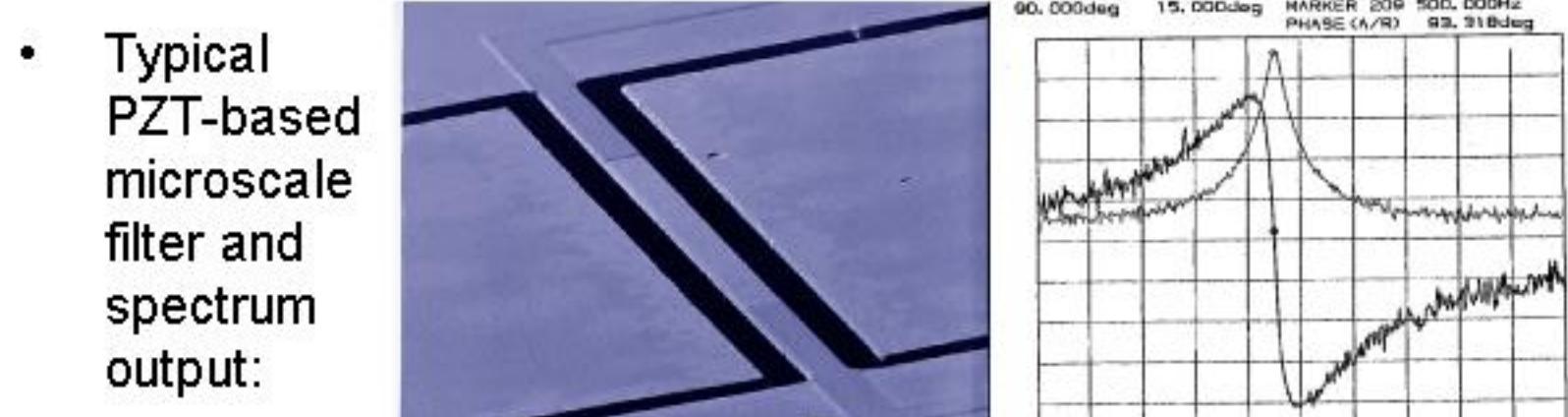
## AlAs Piezo Characterization



## AlGaAs/AlAs/AlGaAs resonator fabrication



- Major challenges remain to be addressed for nanoresonators in filter applications:
  - impedance matching
  - adsorption effects / mass sensitivity
  - thermal stability
  - SNR limits
- Piezoelectric transduction can reduce the impact of these issues by enabling larger-scale high frequency resonators into the S-band range



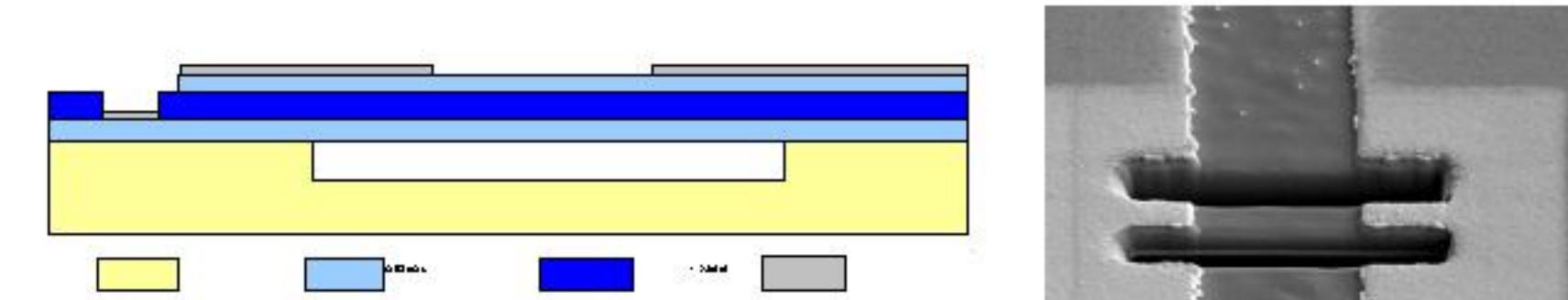
- Related designs in progress:
  - bending mode resonators (use  $d_{31}$ , with higher modes, new anchor designs)
  - shear mode block resonators (use high  $d_{14}$ )
  - thickness mode disk resonators (use  $d_{31}$ , but higher Q expected)

## AlAs Piezoelectric Filters

	Si	GaAs	AlAs	
$\rho$ [kg/m³]	2330	5360	3760	moderate density
E [GPa]	166	118	120	moderate stiffness
$f_n \sim (E/\rho)^{1/2}$	$f_{Si}$	$0.55f_{Si}$	$0.67f_{Si}$	higher $f_n$ than GaAs
$-d_{31}$ [pC/m]	---	1.34	1.91	strong relative piezo
$\epsilon_r$	---	10.9	8.2	lower capacitance
$k^2$	---	---	0.08	Coupling > ZnO, AlN

- AlAs is an excellent material for nanoscale resonators
- Higher piezoelectric coupling than ZnO, AlN, GaAs
- Good fracture toughness, ultimate yield strength
- moderate density and stiffness for higher frequencies than GaAs
- Single xtal epitaxial growth, lattice match to GaAs for high Q

- GaAs micromachining used for device release
- Typical anisotropic etch profiles shown at right
- 3-layer heterostructures fabricated via MBE, FIB, and wet etching
- plasma etching processes under development for selective AlGaAs/AlAs etching
- initial microscale structures designed for  $d_{31}$ ,  $d_{33}$ , Q,  $f_n$  measurements
- epitaxial regrowth for future devices
- Typical clamped-clamped beam AlAs heterostructure structure patterned by FIB:



## AlAs/GaAs bulk micromachining:

